

Application/Control No.	Applicant(s)/Patent under Reexamination
10/068,159	TAN ET AL.
Examiner	Art Unit
Thao P. Le	2818

SEARCHED						
Class	Subclass	Date	Examiner			
257	777	4/27/2007	T.LE			
257	778	4/27/2007	T.LE			
257	E23.069	4/27/2007	T.LE			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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interference (see note)		4/27/2007	T.LE	

	SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR			
east (see note)	4/27/2007	T.LE			
IDS + east (see search)	4/27/2007	T.LE			
					